

LOOK-AHEAD CARRY GENERATOR |

S54182 N74182

\$54182-B,F,W • N74182-B,F

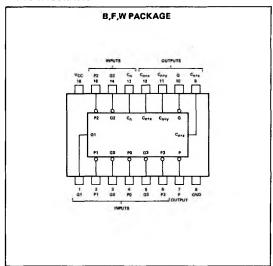
DIGITAL 54/74 TTL SERIES

DESCRIPTION

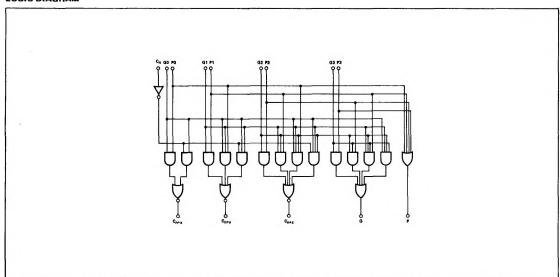
The S54182, N74182 is a high-speed, look-ahead carry generator capable of anticipating a carry across four binary adders or group of adders. It is cascadable to perform full look-ahead across n-bit adders, with only 13 nanoseconds delay for each level of look-ahead. Carry, generate-carry, and propagate-carry functions are provided as enumerated in the pin designation table above.

The S54182 or N74182, when used in conjunction with the S54181 or N74181 arithmetic logic unit (ALU), provides full high-speed carry look-ahead capability for up to n-bit words. Each S54182/N74182 generates the look-ahead (anticipated carry) across a group of four ALUs and, in addition, other carry look-ahead circuits may be employed to anticipate carry across sections of four look-ahead packages up to n-bits. Applications data for the S54181/N74181 illustrates cascading of S54182/N74182 circuits to perform multi-level look-ahead.

PIN CONFIGURATIONS



LOGIC DIAGRAM



RECOMMENDED OPERATING CONDITIONS

| | S54182 | | | N74182 | | | |
|--|--------|-----|-----|--------|-----|------|------|
| | MIN | NOM | MAX | MIN | NOM | MAX | UNIT |
| Supply Voltage V _{CC} | 4.5 | 5 | 5.5 | 4.75 | 5 | 5.25 | V |
| Normalized Fan-Out from each Output, N: High logic level | | | 20 | | | 20 | |
| Low logic level | | | 10 | | | 10 | l |
| Operating Free-Air Temperature Range, TA | -55 | 25 | 125 | 0 | 25 | 70 | °с |

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

| | PARAMETER | Т т | TEST CONDITIONS* | | | TYP** | MAX | UNIT |
|-----------------|--|---|---|---|-----|----------|----------|------|
| VIH | High-level input voltage | | | | Ž | • | | |
| VIL | Low-level input voltage | | | | | | 8.0 | v |
| v _{oh} | High-level output voltage | V _{CC} = MIN, V _{IL} = 0.8V, | V _{IH} = 2V, I _{OH} = ~800μA | | 2.4 | | | v |
| VOL | Low-level output voltage | V _{CC} = MIN, V _{IL} = 0.8V, | | | | | 0.4 | v |
| I _{IH} | High-level input current (Cn input) | | | | | | 80 | μΑ |
| Чн | High-level input current (P3 input) | | | | | | 120 | μΑ |
| Чн | High-level input current (P2 input) | | | | | | 160 | μА |
| ιн | High-level input current (P0, P1, or G3 input) | V _{CC} = MAX, | V _I = 2.4V | | | | 200 | μΑ |
| I _{IH} | High-level input current (G0 or G2 input) | | | | | | 360 | μΑ |
| ΉΗ | High-level input current (G1 input) | | | | | | 400 | μΑ |
| ι _{IH} | High-level input current (any input) | V _{CC} = MAX, | V _I = 5.5V | | | | 1 | mA |
| I _{IL} | Low-level input current (Cn input) | | | | | | -3.2 | mA |
| ^I IL | Low-level input current (P3 input) | | | | | | -4.8 | mA |
| 1 _{IL} | Low-level input current (P2 input) | | | | | | -6.4 | mA |
| I _{IL} | Law-level input current (PO, P1, or G3-input) | V _{CC} = MAX, | V _I = 0.4V | , | | | -8 | mA |
| I _{IL} | Low-level input current (G0 or G2 input) | | | | | | -14.4 | mA |
| I _{IL} | Low-level input current (G1 input) | | | | | | -16 | mA |
| los | Short-circuit output current † | V _{CC} = MAX | | | -40 | | -100 | mA |
| ССН | Supply current, all outputs high | V _{CC} = MAX | S541 N74 | | | 27 27 | | mA |
| CCL | Supply current, all outputs low | V _{CC} = MAX | S541 N74 | | | 45 45 | 65 72 | mA |

SWITCHING CHARACTERISTICS, V_{CC} = 5V, T_A = 25°C, N = 10

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|------------------------------------|----------------------------------|----------------------------------|-----|-----|-----|------|
| | Propagation delay time, low-to- | | | 44 | 17 | |
| ^t PLH high-level output | 0 45.5 | | 11 | 17 | ns | |
| | Propagation delay time, high-to- | $C_L = 15pF$, $R_L = 400\Omega$ | | 45 | 22 | |
| ^t PHL | low-level output | | | 15 | | ns |

^{*} For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

^{**} All typical values are at V_{CC} = 5V, T_A = 25°C.

Not more than one output should be shorted at a time and duration of the short-circuit test should not exceed one second.